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Atom Probe Field Ion Microscopy and Related Topics: A Bibliography 1990

K. F. Russell
M. K. Miller

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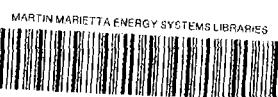
**ATOM PROBE FIELD ION MICROSCOPY AND RELATED TOPICS:
A BIBLIOGRAPHY 1990**

**K. F. Russell
M. K. Miller**

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PREFACE

This bibliography includes references related to the following topics: atom probe field ion microscopy (APFIM), field ion microscopy (FIM), field emission (FE), ion sources, and field desorption mass microscopy (FDMM). Technique-orientated studies and applications are included.

This bibliography covers the period 1990. Previous publications, *Atom Probe Field-ion Microscopy and Related Topics: A Bibliography 1978-1987*, compiled by M. K. Miller and A. R. McDonald, ORNL/TM-11157; *Atom Probe Field-Ion Microscopy and Related Topics: A Bibliography 1988*, compiled by M. K. Miller and A. R. Hawkins, ORNL/TM-11370; *Atom Probe Field Ion Microscopy and Related Topics: A Bibliography 1989*, compiled by M. K. Miller, A. R. Hawkins, and K. F. Russell, ORNL/TM-11696, Oak Ridge National Laboratory, Oak Ridge, TN 37831-6285; and *Field-Ion Microscopy and Related Techniques, A Bibliography: 1951-1978*, compiled by R. E. Thurstans and J. M. Walls, published by Warwick, Birmingham, contain the papers published prior to this period.

The references contained in this document were compiled from a variety of sources including computer searches and personal lists of publications. To reduce the length of this document, the references have been reduced to the minimum necessary to locate the articles. The references, listed alphabetically by authors, are subdivided into the categories listed in paragraph one above. An *Addendum* of references missed in previous bibliographies is included.

We would like to thank Dr. G. D. W. Smith of Oxford University, Dr. L. L. Horton of Oak Ridge National Laboratory (ORNL), and M. Alexander of the ORNL Central Library for their stoic efforts in the preparation of this document. We would also like to thank the many authors for supplying their personal publications lists, and we apologize for any errors or omissions that may have occurred in compiling this document.

K. F. Russell and M. K. Miller
Metals and Ceramics Division

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